

OptiMOS® Power-Transistor

Features

- N-channel Enhancement mode
- Automotive AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green package (lead free)
- Ultra low Rds(on)
- 100% Avalanche tested

Product Summary

V _{DS}	55	V
R _{DS(on),max} (SMD version)	8.8	mΩ
I _D	80	Α

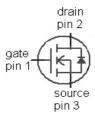
PG-TO263-3-2

PG-TO220-3-1





Туре	Package	Ordering Code	Marking
IPB80N06S2-09	PG-TO263-3-2	SP0002-18741	2N0609
IPP80N06S2-09	PG-TO220-3-1	SP0002-18740	2N0609



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	I _D	T _C =25 °C, V _{GS} =10 V	80	А
		T _C =100 °C, V _{GS} =10 V ²⁾	80	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	320	
Avalanche energy, single pulse ²⁾	E _{AS}	/ _D = 80 A	370	mJ
Gate source voltage ⁴⁾	V_{GS}		±20	V
Power dissipation	P _{tot}	T _C =25 °C	190	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 +175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R _{thJC}		-	-	0.8	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}		-	-	62	
SMD version, device on PCB R_{thJA}	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ⁵⁾	-	-	40	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D = 1 mA	55	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 125 \mu{\rm A}$	2.1	3.0	4.0	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =55 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	-	0.01	1	μA
		$V_{\rm DS}$ =55 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C ²⁾	-	1	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =50 A,	1	7.6	9.1	mΩ
		$V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, SMD version	-	7.3	8.8	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	C iss		-	2360	-	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =25 V, f=1 MHz	-	610	-	1
Reverse transfer capacitance	C _{rss}		-	150	-	
Turn-on delay time	$t_{d(on)}$		1	14	1	ns
Rise time	t _r	V _{DD} =30 V, V _{GS} =10 V,	-	29	-	
Turn-off delay time	t _{d(off)}	$I_{\rm D}$ =80 A, $R_{\rm G}$ =4.7 Ω	-	39	-	
Fall time	t _f		-	28	-	
Gate Charge Characteristics ²⁾						
Gate to source charge	Q _{gs}		-	12	16	nC
Gate to drain charge	Q_{gd}	V _{DD} =44 V, I _D =80 A, V _{GS} =0 to 10 V	-	24	37	
Gate charge total	Q _g		-	60	80	
Gate plateau voltage	$V_{ m plateau}$		-	5.5	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	− T _C =25 °C	-	-	80	Α
Diode pulse current ²⁾	I _{S,pulse}		-	-	320	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =80 A, T _j =25 °C	-	0.9	1.3	V
Reverse recovery time ²⁾	t _{rr}	V_R =30 V, I_F = I_S , di_F / dt =100 A/ μ s	-	50	63	ns
Reverse recovery charge ²⁾	Q _{rr}]	-	76	95	nC

 $^{^{1)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ = 0.8 K/W the chip is able to carry 99 A at 25°C. For detailed information see Application Note ANPS071E at www.infineon.com/optimos

²⁾ Defined by design. Not subject to production test.

³⁾ See diagram 13.

⁴⁾ Qualified at -20V and +20V.

 $^{^{5)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



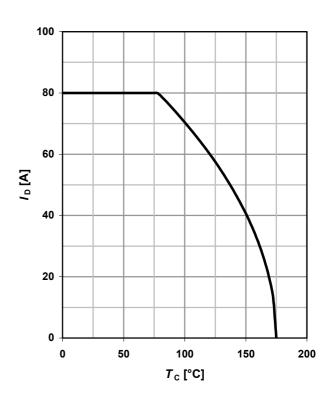
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

200 180 160 140 120 P_{tot} [W] 100 80 60 40 20 0 50 100 200 0 150 *T*_c [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



3 Safe operating area

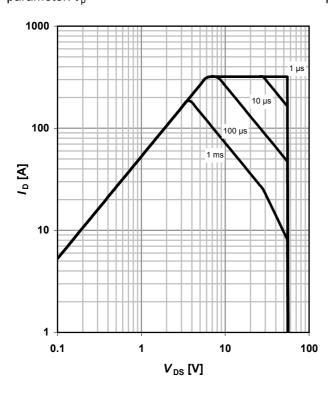
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

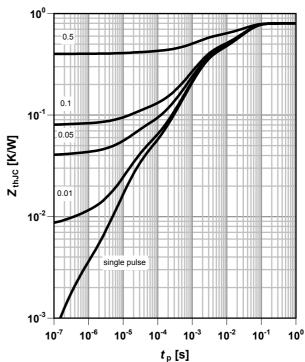
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D = t_p/T$



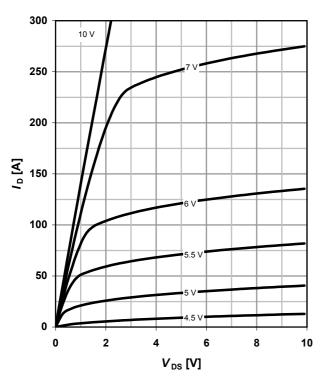




5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

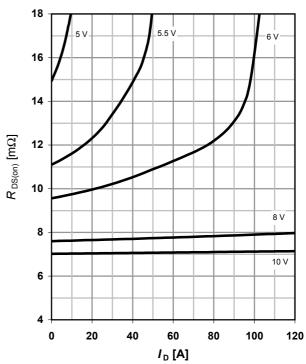
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ }^{\circ}\text{C}$

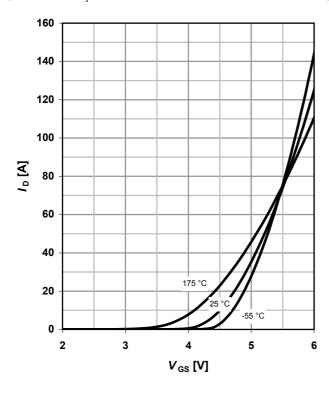
parameter: V_{GS}



7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$

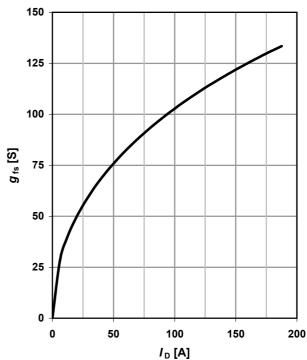
parameter: T_i



8 Typ. Forward transconductance

 $g_{fs} = f(I_D); T_j = 25^{\circ}C$

parameter: g fs

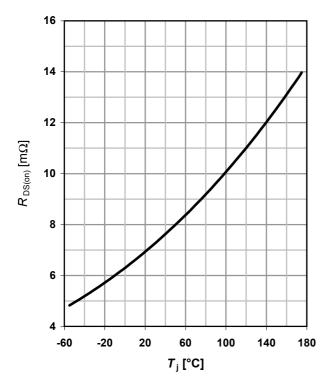




9 Typ. Drain-source on-state resistance

 $R_{DS(ON)} = f(T_i)$

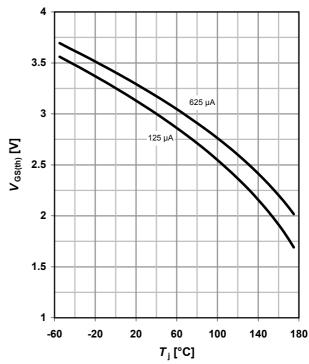
parameter: I_D = 80 A; V_{GS} = 10 V



10 Typ. gate threshold voltage

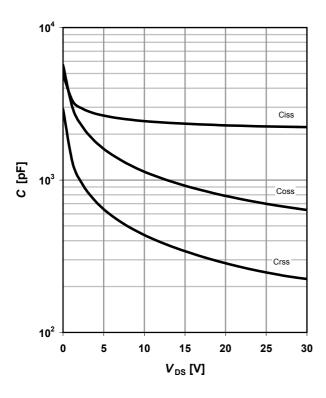
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D



11 Typ. capacitances

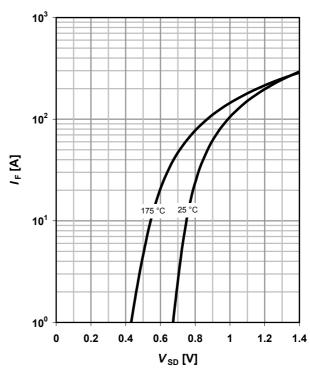
 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$



12 Typical forward diode characteristicis

 $IF = f(V_{SD})$

parameter: T_i





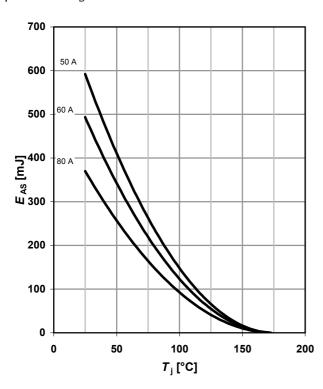
13 Typical avalanche energy

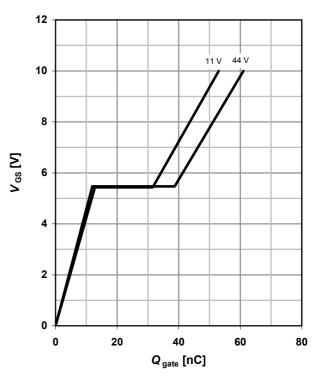
$E_{AS} = f(T_i)$

parameter: I_D

14 Typ. gate charge

$$V_{\rm GS}$$
 = f($Q_{\rm gate}$); $I_{\rm D}$ = 80 A pulsed

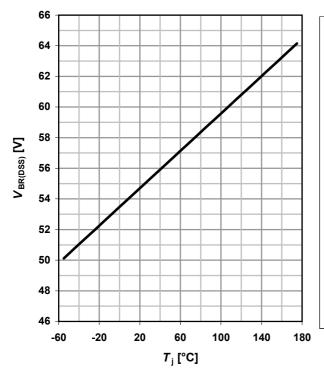


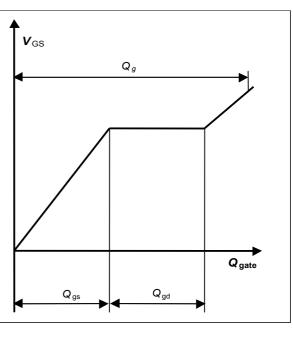


15 Typ. drain-source breakdown voltage

 $V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$









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